

Initial Evaluation of a Micro-CMM

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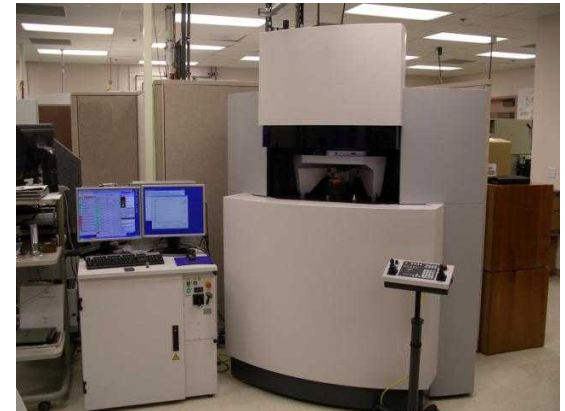
A new class of CMMs is available.

- **Small work volumes**
 - typically 100mm x 100mm x 100mm
- **Fine positional accuracy**
 - <300nm
- **Low contact force**
 - <1mN



SNL has acquired a micro-CMM.

- Meso-scale manufacturing and system development department
 - 10^1 mm in size
 - 10^{-1} mm features
 - 10^{-3} mm tolerances
- MPE_E of $(0.250+L/666)\mu\text{m}$
- 0.5mN probing force
- 100mm x 100mm x 100mm work volume
- Tactile and vision probes
- Surveillance camera for operation



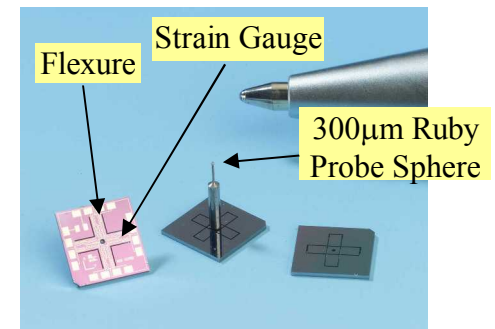
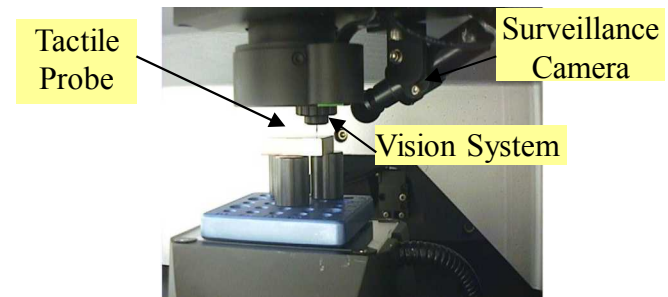


Precision design principles support accuracy claims by vendor

- **Dual bridge design minimizes Abbe offsets**
- **Air bearing design modifications increases stiffness**
 - **>40 air bearings**
- **Active vibration isolation**
- **Thermal shielding**
- **Glass scales**
- **Linear motors**
 - **Heat generation proportional to load**

Silicon flexure tactile probe applies low contact force, $\sim 0.5\text{mN}$

- $120\mu\text{m}$ and $300\mu\text{m}$ diameter probes readily available
- Flexure + strain gauge sensing technology
 - Analog nature enables scanning
- Force-deflection response linearized during special calibration
- Max deflection is $\sim 100\mu\text{m}$



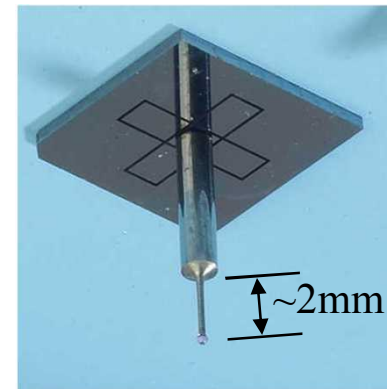
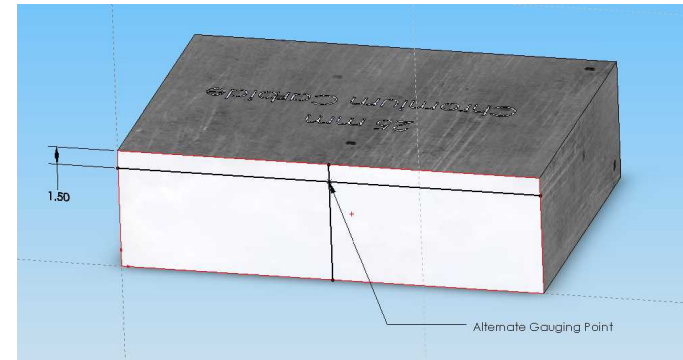


Force-Deflection Linearization Video

Probe Boss
Factor
Calibration

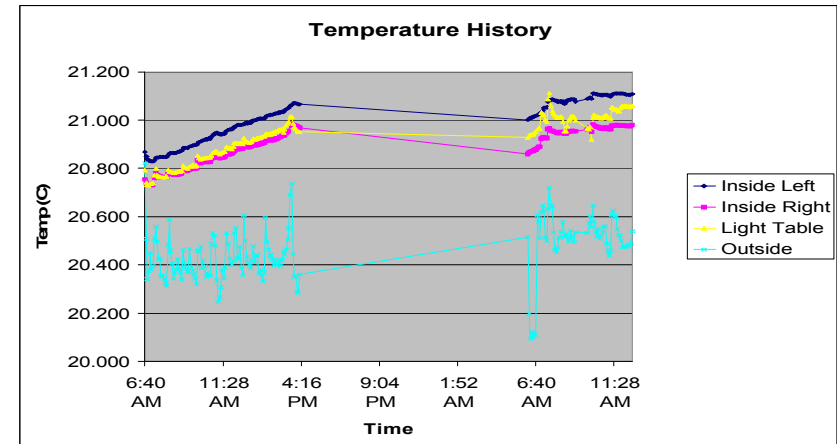
Evaluation requires special calibration of gauge blocks

- Shank length is approximately 2mm
- Unable to reach standard gauging point
- Alternate gauging point as shown
- Certification by SNL primary standards laboratory on gauge block interferometer



Temperature and cleanliness are important at these levels

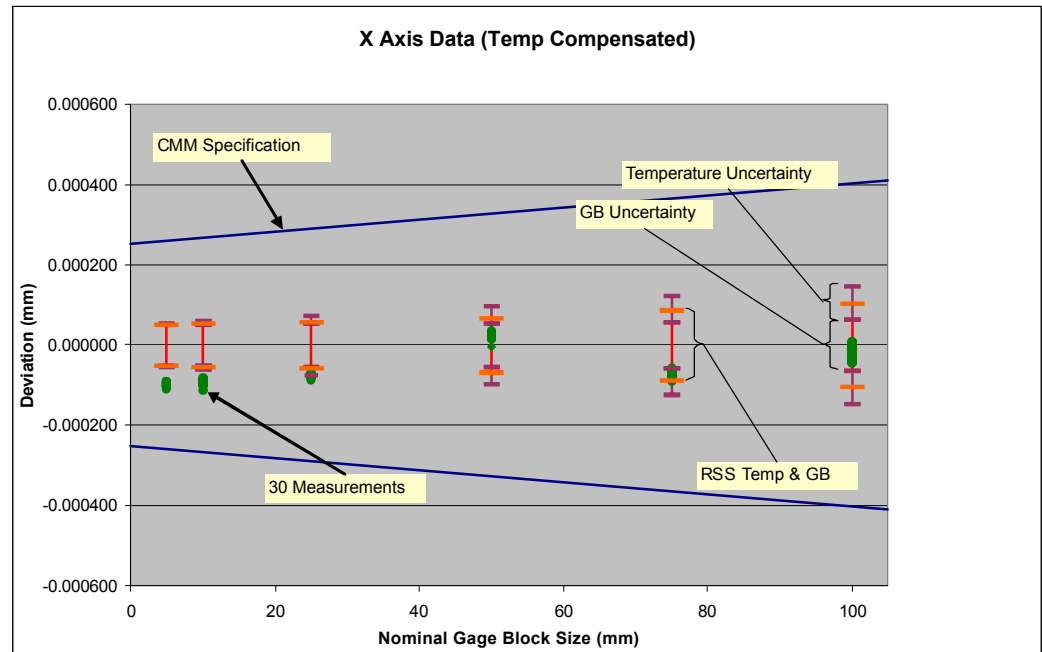
- **Temperature**
 - Absolute and gradient restrictions
 - Manual thermal compensation for this study
 - Minimize handling
- **Cleaning**
 - Spectroscopic grade IPA and acetone
 - Probe is delicate



Probe
Cleaning

X-Axis Results

- Excellent repeatability
- Well within specification

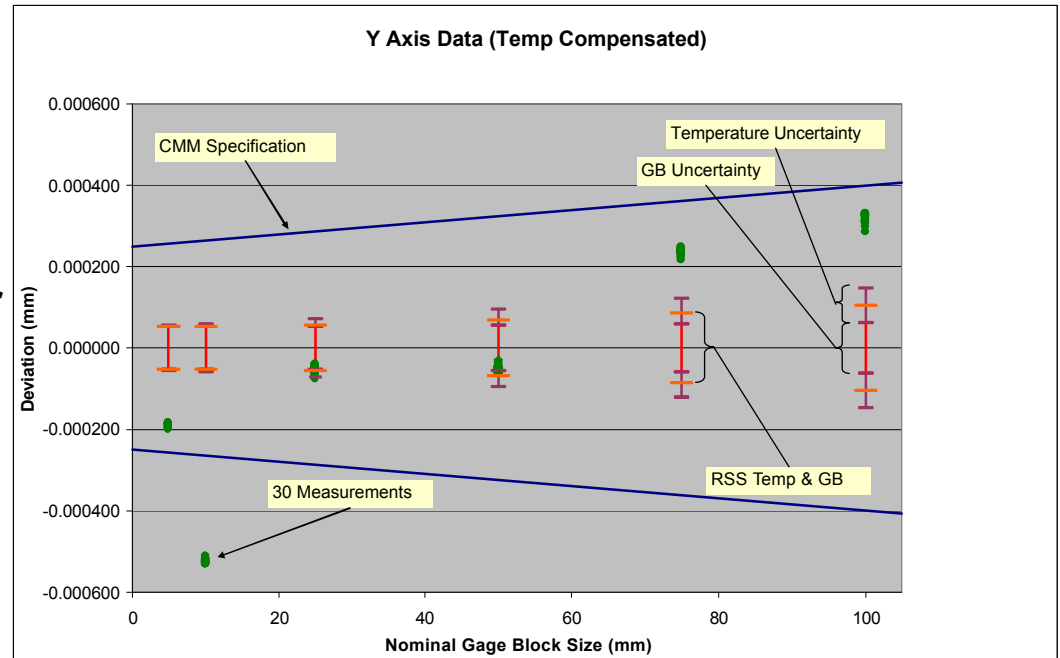


Temperature compensated x-axis results.

	5mm	10mm	25mm	50mm	75mm	100mm
Range	21 nm	32	16	45	32	54
Average	-98 nm	-93	-77	25	-74	-17
Std. Dev.	5 nm	6	4	10	7	16
F25 Spec +/-	258 nm	265	288	325	363	400

Y-Axis Results

- Excellent repeatability
- One set of outliers
 - Dust?
 - Not supported by other measurements
- Balance within specification

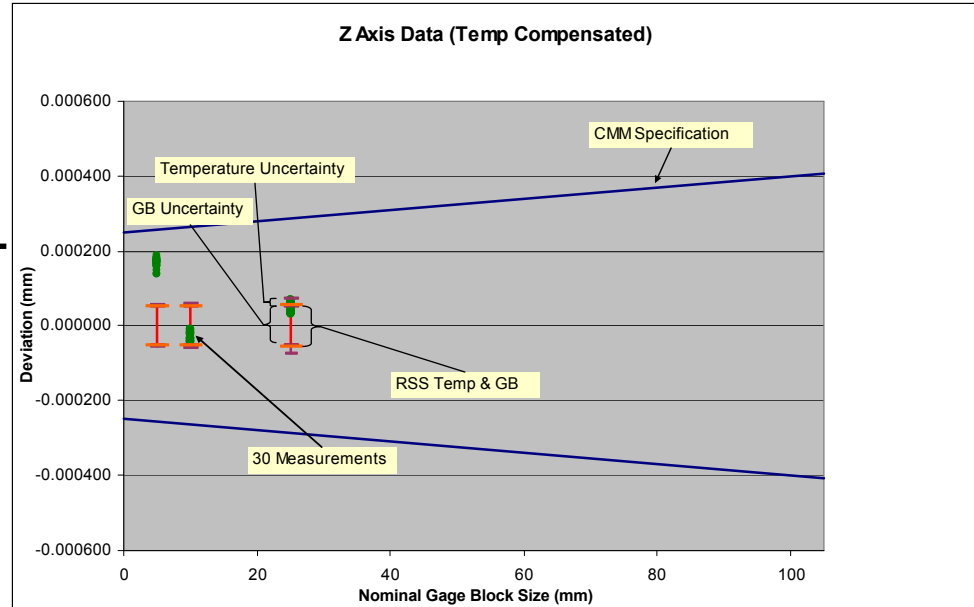


Temperature Compensated Y-Axis Results.

	5mm	10mm	25mm	50mm	75mm	100mm
Range	17 nm	22	37	33	35	49
Average	191 nm	-524	-54	-49	237	320
Std. Dev.	5 nm	5	8	7	7	11
F25 Spec +/-	258 nm	265	288	325	363	400

Z-Axis Results

- Mechanical constraints reduce gauge block set
- Sample repeatability as x- and y- axes
- Within specification



Temperature compensated z-axis data.

	5mm	10mm	25mm	50mm	75mm	100mm
Range	50 nm	45	41	NA	NA	NA
Average	168 nm	-31	49	NA	NA	NA
Std. Dev.	11 nm	12	12	NA	NA	NA
F25 Spec +/-	258 nm	265	288	325	363	400



Squareness Results

- 75mm gauge block in x-y plane
- 0.675 arcsec out-of square

Squareness data.

	75mm (+X,+Y)	75mm (-X,+Y)
Range	21 nm	63
Average	-205 nm	286
Std. Dev.	5 nm	14



Important considerations for micro-CMMs

- **High purity cleaners**
- **No canned/compressed air**
 - **High force**
 - **Cools parts**
- **Mechanical cleaning of probes may be done with extreme care**
- **Linearization and offset for force-deflection curve**
 - **Slope: Once per installation**
 - **Intercept: Daily**



Conclusions and future work

- Initial results are encouraging
- 4:1 measurements at the $1\mu\text{m}$ level are certainly achievable
- Current machine is not error mapped
- Upgrade machine installation in progress
- Calibration artifact for hybrid tactile-vision system under development

